



EE 232 Lightwave Devices

Lecture 20: Noises in Photodetectors

Reading: Yariv 10.3-10.5 or Chuang 15.1.3

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Poisson Distribution

Poisson distribution:

a given event occurring in any time interval is distributed uniformly over the interval.

The probability of n electrons arriving in a period T : is

$$p(n) = \frac{\bar{n}^n e^{-\bar{n}}}{n!}$$

where \bar{n} is the average number of electrons arriving in T

Properties of Poisson Distribution:

Mean = \bar{n}

Variance = \bar{n}

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Spectral Density Function

Random variable $i(t)$ consists of a large number of individual events (e.g., single-electron photocurrent) at random time:

$$i(t) = \sum_{i=1}^{N_T} f(t - t_i), \quad 0 \leq t \leq T$$

Fourier transform: $I_T(\omega) = \sum_{i=1}^{N_T} F_i(\omega)$

$$F_i(\omega) = \frac{1}{2\pi} \int_{-\infty}^{\infty} f(t - t_i) e^{-i\omega t} dt = \frac{e^{-i\omega t_i}}{2\pi} \int_{-\infty}^{\infty} f(t) e^{-i\omega t} dt = e^{-i\omega t_i} F(\omega)$$

$$\langle |I_T(\omega)|^2 \rangle = \left\langle |F(\omega)|^2 \left\{ N_T + \sum_{i=1}^{N_T} \sum_{j=1}^{N_T} e^{-i\omega(t_i - t_j)} \right\} \right\rangle = \overline{N_T} |F(\omega)|^2 = \overline{N} T |F(\omega)|^2$$

\overline{N} : average rate of electron arrival

Spectral density function: $S(v) = \lim_{T \rightarrow \infty} \frac{8\pi^2 |I_T(2\pi v)|^2}{T} = 8\pi^2 \overline{N} |F(2\pi v)|^2$

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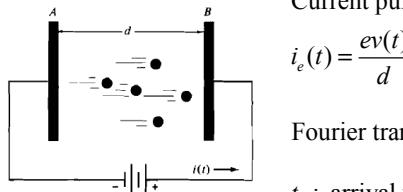
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Shot Noise

Shot Noise: Noise current arising from random generation and flow of mobile charge carriers.

Current pulse due to a single electron moving at $v(t)$:



$$i_e(t) = \frac{ev(t)}{d}$$

Fourier transform: $F(\omega) = \frac{1}{2\pi} \frac{e}{d} \int_0^{t_a} v(t) e^{-i\omega t} dt$

t_a : arrival time, $x(0) = 0$, $x(t_a) = d$,

Small transit time t_a , $\omega t_a \ll 1 \rightarrow e^{-i\omega t_a} \approx 1$

$$F(\omega) = \frac{1}{2\pi} \frac{e}{d} \int_0^{t_a} dx \cdot dt = \frac{1}{2\pi} \frac{e}{d} \int_0^d dx = \frac{e}{2\pi}$$

$$S(v) = 8\pi^2 \overline{N} \left(\frac{e}{2\pi} \right)^2 = 2e\bar{I}$$

$$\bar{I} = e\overline{N}$$

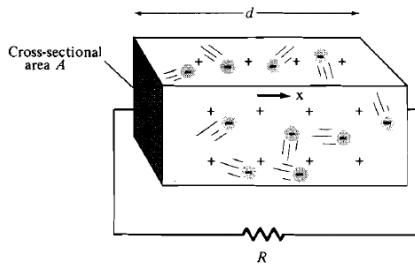
$$\boxed{i_N^2(v) = S(v)dv = 2e\bar{I}dv}$$

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Thermal Noise (Johnson Noise)



- Fluctuation in the voltage across a dissipative circuit element (resistor)
- Caused by thermal motion of charged carriers

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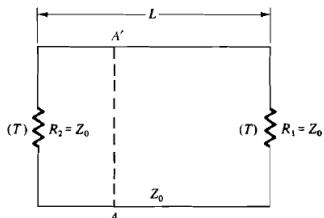


Thermal Noise Derivation

Consider two resistors connected by a lossless transmission line of length L :

voltage wave: $v(t) = A \cos(\omega t \pm kz)$

Assume periodic condition: $kL = 2m\pi$



Mode density: $\rho(\nu) = \frac{L}{c}$

Power flow: $P = \frac{\text{Energy}}{\text{Transit Time}}$

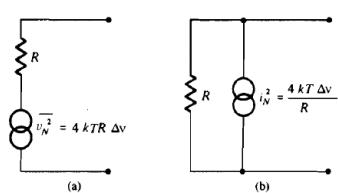
$$P = \frac{1}{L/c} \left(\frac{L}{c} \Delta\nu \right) \left(\frac{hv}{e^{hv/k_B T} - 1} \right) = \frac{hv \Delta\nu}{e^{hv/k_B T} - 1}$$

$hv / k_B T \ll 1$

$$P = k_B T \Delta\nu = \left(\overline{v_N^2} \left(\frac{R}{R+R} \right)^2 \right) \frac{1}{R} = \left(\overline{i_N^2} \left(\frac{R}{R+R} \right)^2 \right) R$$

Equivalent mean square noise voltage: $\boxed{\overline{v_N^2} = 4k_B T R \Delta\nu}$

Equivalent mean square noise current: $\boxed{\overline{i_N^2} = \frac{4k_B T \Delta\nu}{R}}$



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Noise in p-i-n Photodiode

Noises in p-i-n photodiodes: shot noise and thermal noise

$$\overline{i_N^2(v)} = \overline{i_{N,shot}^2(v)} + \overline{i_{N,thermal}^2(v)} = 2e\bar{I}dv + \frac{4k_B T \Delta v}{R}$$

Signal:

$$i_S^2(v) = \bar{I}^2$$

Signal to noise ratio (SNR):

$$SNR = \frac{\bar{I}^2}{2e\bar{I}dv + \frac{4k_B T \Delta v}{R}}$$

Note that the SNR improves with increasing average photocurrent \bar{I}

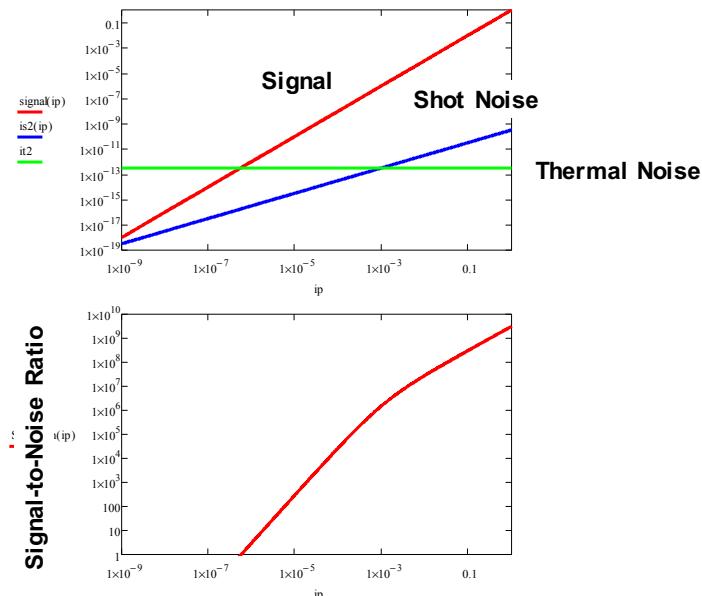
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Example

$B = 1 \text{ GHz}$
 $R = 50$



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